

**Notice of References Cited**

Application/Control No.

09/940,757

Applicant(s)/Patent Under  
Reexamination  
WEI ET AL.

Examiner

Minh Trinh

Art Unit

3729

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5796211	08-1998	Graebner et al	315/3.5
	B	US-5817201	10-1998	Creschner et al	156/150
	C	US-4683399	07-1987	Soclof	313/537
	D	US-6297592	10-2001	Groren et al	315/3.5
	E	US-6495865	12-2002	Johnson et al	257/164
	F	US-6448709	09-2002	Chuang et al	313/497
X	G	US-2003/0041438	03-2003	Wei et al	29/601
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2000-141056	05-2000	Japan	Bower et al	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.